Scanning Tunneling Microscopy of the Topological Insulator Bi$_2$Se$_3$As$_x$  

TESS WILLIAMS, ANJAN SOUMYANARAYANAN, Harvard University, DILLON GARDNER, SHAOYAN CHU, YOUNG LEE, Massachusetts Institute of Technology, JENNIFER E. HOFFMAN, Harvard University — We use a low temperature scanning tunneling microscope to study the topological insulator Bi$_2$Se$_3$As$_x$. We present atomic resolution topographies displaying three-fold symmetric impurities. We identify features in the density of states.

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